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<u>L4</u>	generat\$3 same trigger same output same condition	11198	<u>L4</u>
<u>L3</u>	generat\$3 trigger same output same condition	1989782	<u>L3</u>
<u>L2</u>	compar\$3 same (trigger adj1 condition) same bus	20	<u>L2</u>
<u>L1</u>	compar\$3 near5 (trigger adj1 condition) near10 bus	2	<u>L1</u>

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<u>L5</u>	L4 same (compar\$3 near10 monitor\$3)	36	<u>L5</u>	
<u>L4</u>	generat\$3 same trigger same output same condition	11198	<u>L4</u>	
<u>L3</u>	generat\$3 trigger same output same condition	1989782	<u>L3</u>	
<u>L2</u>	compar\$3 same (trigger adj1 condition) same bus	20	<u>L2</u>	
<u>L1</u>	compar\$3 near5 (trigger adj1 condition) near10 bus	2	<u>L1</u>	

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<u>L8</u>	714/47,30,25,45,726,39;710/100,52;712/33,35;717/128,129;713/502;345/10,700.ccls.	7898
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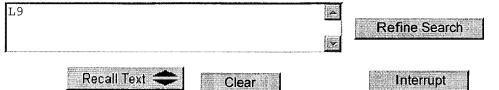
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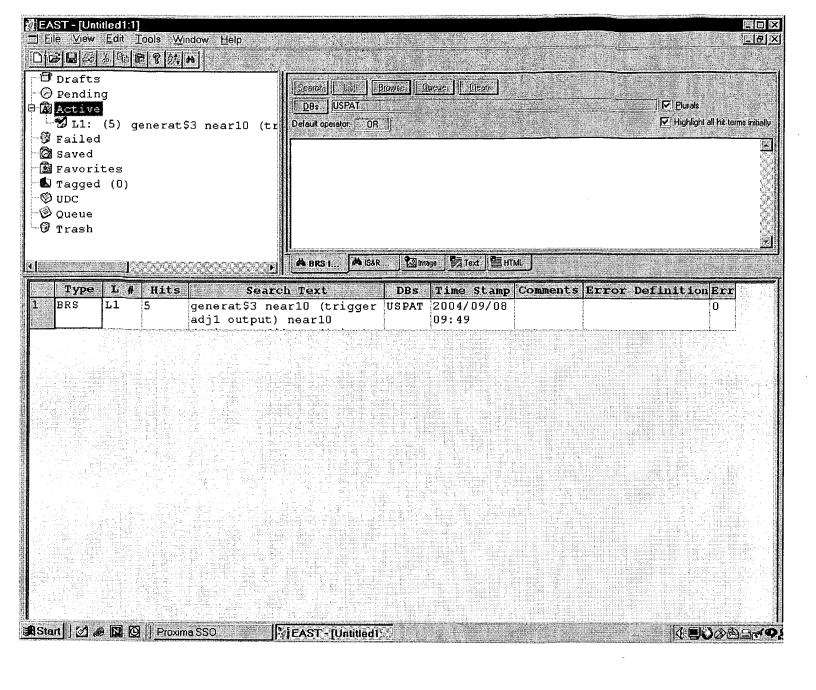


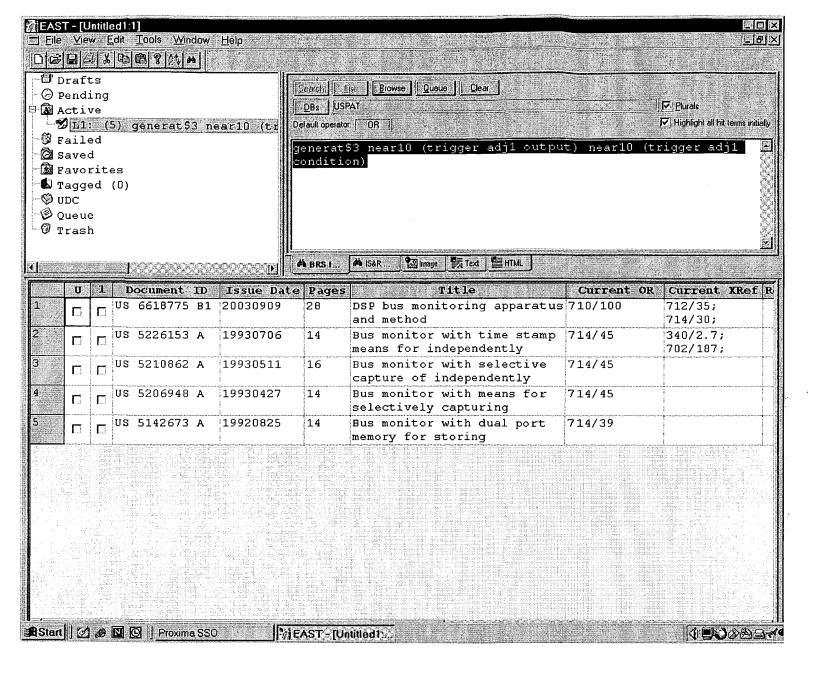
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<u>L8</u>	714/47, 30, 25, 45, 726, 39; 710/100, 52; 712/33, 35; 717/128, 129; 713/502; 345/10, 700. ccls.	7898
DB	EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR	
<u>L7</u>	L6	0
DB	=PGPB,USPT,USOC; PLUR=YES; OP=OR	
<u>L6</u>	12 or L5	54
<u>L5</u>	L4 same (compar\$3 near10 monitor\$3)	36
<u>L4</u>	generat\$3 same trigger same output same condition	11198
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<u>L2</u>	compar\$3 same (trigger adj1 condition) same bus	20
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3 The breakdown fields and risetimes of select gases under the condiof fast charging (/spl sim/ 20 ns and less) and high pressures (20-10

Pulsed Power Plasma Science, 2001. PPPS-2001. Digest of Technical Papers , Volume: 1 , 17-22 June 2001 Pages:482 - 486 vol.1

[Abstract] [PDF Full-Text (487 KB)] **IEEE CNF**

4 The influence of electron density on the formation of streamers in electrical discharges triggered with ultrashort laser pulses La Fontaine, B.; Vidal, F.; Comtois, D.; Ching-Yuan Chien; Desparois, A.; Joh T.W.; Kieffer, J.-C.; Mercure, H.P.; Pepin, H.; Rizk, F.A.M.;

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c e e c Plasma Science, IEEE Transactions on , Volume: 27 , Issue: 3 , June 1999 Pages: 688 - 700

[Abstract] [PDF Full-Text (248 KB)] IEEE JNL

5 Analysis of a passive superconducting fault current limiter

Cha, Y.S.; Zhongjin Yang; Turner, L.R.; Poeppel, R.B.;

Applied Superconductivity, IEEE Transactions on , Volume: 8 , Issue: 1 , Marc 1998

Pages: 20 - 25

[Abstract] [PDF Full-Text (188 KB)] IEEE JNL

6 Voltage pulse forming dynamics in a transmission line section empl photoconductive charging and discharging

Buck, J.A.; Kesler, M.P.;

Microwave Theory and Techniques, IEEE Transactions on , Volume: 42 , Issue

9 , Sept. 1994

[Abstract]

Pages:1632 - 1637

[PDF Full-Text (504 KB)] IEEE JNL

7 Dynamics of fibrin clot lysis under flow conditions by erythrocyte-lintPA

Goel, M.S.; Murciano, J.-C.; Medinilla, S.; Yamamoto, A.; Cines, D.B.; Muzyk, V.R.; Diamond, S.L.;

[Engineering in Medicine and Biology, 2002. 24th Annual Conference and the Annual Fall Meeting of the Biomedical Engineering Society] EMBS/BMES Conference, 2002. Proceedings of the Second Joint, Volume: 1, 2002 Pages: 520 vol.1

[Abstract] [PDF Full-Text (163 KB)] IEEE CNF

8 The Atlas load protection switch

Davis, H.A.; Ballard, E.O.; Dorr, G.; Martinez, M.; Gribble, R.F.; Nielsen, K.E. Pierce, D.; Parsons, W.M.;

Pulsed Power Conference, 1999. Digest of Technical Papers. 12th IEEE

International, Volume: 2, 27-30 June 1999

Pages:941 - 944 vol.2

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The Atlas load protection switch

Pierce, D. Nielsen, K.E. Davis, H.A. Ballard, E.O. Dorr, G. Martinez, M. Gribble, R.F.

Parsons, W.M.

os Alamos Nat. Lab., NM, USA;

This paper appears in: Pulsed Power Conference, 1999. Digest of Technical

Papers. 12th IEEE International

Meeting Date: 06/27/1999 - 06/30/1999

Location: Monterey, CA USA

Publication Date: 27-30 June 1999

On page(s): 941 - 944 vol.2

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Atlas is a high-energy pulsed-power facility under development to study materials Abstract:

properties and hydrodynamics experiments under extreme conditions. Atlas will implode heavy liner loads (m~45 gm) with a peak current of 27-32 MA delivered in 4 µs, and is energized by 96, 240 kV Marx **generators** storing a total of 23 MJ. A key design requirement for Atlas is obtaining useful data for 95% of all loads installed on the

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charge. Once the capacitors have reached full charge, the switches open on a time scale short compared to the bank charge time, allowing current to flow to the load when the incorporated a set of fast-acting mechanical switches in the Atlas design to reduce the machine. Materials response calculations show current from a prefire can damage the protection switches, short the load through a very low inductance path during system substantially reduced. The design of the load protection switches and test results are trigger pulse is applied. The time window of vulnerability for load damage is thus probability of a prefire damaging the load. These switches, referred to as the load load requiring expensive and time consuming replacement. Therefore, we have presented

Index Terms:

fast-acting mechanical experiments materials properties materials response calculations prefire current trigger pulse 240 KV heavy liner loads implosion high-energy pulsed-power facility hydrodynamics 23 MJ pulsed power switches Atlas load protection switch Marx generators pulsed power supplies protection pulse generators 27 to 32 MA 4 mus 45 g very low inductance path switches

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☐ 1. Document ID: US 20030120980 A1

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File: PGPB

Jun 26, 2003

PGPUB-DOCUMENT-NUMBER: 20030120980

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20030120980 A1

TITLE: System trace unit

PUBLICATION-DATE: June 26, 2003

INVENTOR-INFORMATION:

NAME

CITY

STATE

COUNTRY

RULE-47

Harris, Jeremy G.

Buckinghamshire

GB

US-CL-CURRENT: 714/45

Full Title Citation Front	Review Classification	Date Reference	Sequences	Attachments	Claims	KMC Draw De
		National Advances				
☐ 2. Document ID:	US 6618775 B1					
L9: Entry 2 of 9	Fi	le: USPT			Sep 9,	, 2003

US-PAT-NO: 6618775

DOCUMENT-IDENTIFIER: US 6618775 B1

** See image for Certificate of Correction **

TITLE: DSP bus monitoring apparatus and method

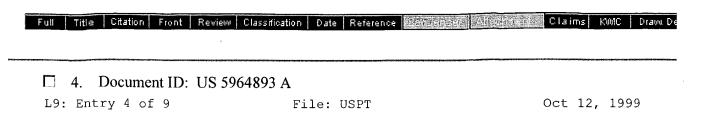
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☐ 3. Document ID: US 6	378092 B1	
L9: Entry 3 of 9	File: USPT	Apr 23, 2002

US-PAT-NO: 6378092

DOCUMENT-IDENTIFIER: US 6378092 B1

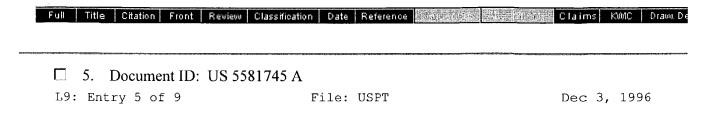
TITLE: Integrated circuit testing



US-PAT-NO: 5964893

DOCUMENT-IDENTIFIER: US 5964893 A

TITLE: Data processing system for performing a trace function and method therefor



US-PAT-NO: 5581745

DOCUMENT-IDENTIFIER: US 5581745 A

TITLE: Apparatus for suspending the bus cycle of a microprocessor by inserting wait states

Full | Title | Citation | Front | Review | Classification | Date | Reference | Contract | Alter Kning vis. | Claims | KWIC | Draw, De

☐ 6. Document ID: US 5226153 A

L9: Entry 6 of 9

File: USPT

Jul 6, 1993

US-PAT-NO: 5226153

DOCUMENT-IDENTIFIER: US 5226153 A

TITLE: Bus monitor with time stamp means for independently capturing and correlating events

Full Title Citation Front Review	Classification Date Reference (Scottist S	Elización elice Claims KMC Draw. De
☐ 7. Document ID: US 52	10862 A	
L9: Entry 7 of 9	File: USPT	May 11, 1993

US-PAT-NO: 5210862

DOCUMENT-IDENTIFIER: US 5210862 A

TITLE: Bus monitor with selective capture of independently occuring events from multiple sources



8.	Document ID:	US 5206948 A

L9: Entry 8 of 9

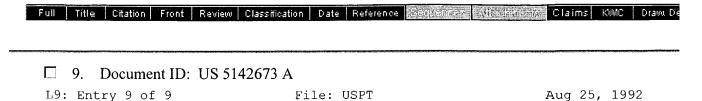
File: USPT

Apr 27, 1993

US-PAT-NO: 5206948

DOCUMENT-IDENTIFIER: US 5206948 A

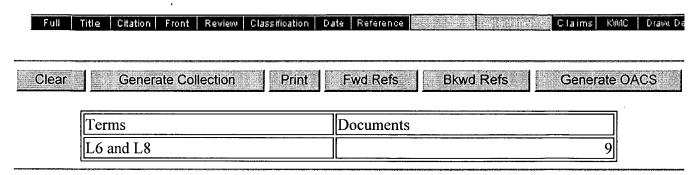
TITLE: Bus monitor with means for selectively capturing trigger conditions



US-PAT-NO: 5142673

DOCUMENT-IDENTIFIER: US 5142673 A

TITLE: Bus monitor with dual port memory for storing selectable trigger patterns



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L9: Entry 2 of 9

File: USPT

Sep 9, 2003

US-PAT-NO: 6618775

DOCUMENT-IDENTIFIER: US 6618775 B1

** See image for Certificate of Correction **

TITLE: DSP bus monitoring apparatus and method

DATE-ISSUED: September 9, 2003

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Davis; Henry A. Soquel CA

ASSIGNEE-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY TYPE CODE

Micron Technology, Inc. Boise ID 02

APPL-NO: 09/ 638461 [PALM]
DATE FILED: August 14, 2000

PARENT-CASE:

CROSS-REFERENCE TO RELATED APPLICATION This application is a continuation of U.S. patent application Ser. No. 09/026,734 filed Feb. 20, 1998 entitled "DSP Bus Monitoring Apparatus And Method", abandoned. Pursuant to 35 U.S.C. .sctn.119(e), this application claims the priority benefit of provisional application No. 60/055,815 filed Aug. 15, 1997.

INT-CL: [07] $\underline{G06}$ \underline{F} $\underline{11/30}$, G06 \underline{F} 13/00

US-CL-ISSUED: 710/100; 714/30, 714/45, 712/35 US-CL-CURRENT: 710/100; 712/35, 714/30, 714/45

FIELD-OF-SEARCH: 714/47, 714/30, 714/25, 714/40, 714/45, 714/39, 710/52, 710/100,

710/305, 712/33, 712/35, 717/128, 717/129, 713/502, 345/10, 345/700

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PAT-NO	ISSUE-DATE	PATENTEE-NAME	US-CL
5142673	August 1992	DeAngelis et al.	395/575
5210862	May 1993	DeAngelis et al.	395/575
5313618	May 1994	Pawloski	395/500.49

	5325368	June 1994	James et al.	714/727
	5329471	July 1994	Swoboda et al.	395/500.44
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	5463760	October 1995	Hamauchi	395/500.49
	5488688	January 1996	Gonzales et al.	710/34
	5513338	April 1996	Alexander et al.	395/500.49
	5530804	June 1996	Edgington et al.	710/30
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	5561761	October 1996	Hicok et al.	714/30
	<u>5566303</u>	October 1996	Tashiro et al.	710/100
	<u>5590354</u>	December 1996	Klapproth et al.	714/30
	<u>5610826</u>	March 1997	Whetsel	364/487
	5621651	April 1997	Swoboda	395/500.44
	5623673	April 1997	Gephardt et al.	710/260
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	5671172	September 1997	Britton	365/45
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	5812830	September 1998	Naasch-Shahry et al.	
	5908392	June 1999	Wilson et al.	600/509
	5960457	September 1999	Skrovan et al.	711/146
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The Right Tools Do the Best Jobs; EDN; Jun., 1997; pp. S.cndot.10--S.cndot.21.

ART-UNIT: 2181

PRIMARY-EXAMINER: Ray; Gopal C.

ATTY-AGENT-FIRM: Gazdzinski & Associates

ABSTRACT:

A bus monitor is provided as a tool for developing, debugging and testing a system having an embedded processor. The bus monitor resides within the same chip or module as the processor, which allows connection to internal processor buses not accessible from external contacts. The monitor uses a separate circular buffer to continuously store, in real-time, data traces from each of one or more internal processor buses. Upon the occurrence of a trigger condition, storage stops and a trace is preserved. Trigger conditions can depend on events occurring on multiple buses and are downloaded via an interface from an external device. Data traces are uploaded via the interface to an external device for evaluation of processor operation.

13 Claims, 45 Drawing figures

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L9: Entry 9 of 9

File: USPT

MA

Aug 25, 1992

US-PAT-NO: 5142673

DOCUMENT-IDENTIFIER: US 5142673 A

TITLE: Bus monitor with dual port memory for storing selectable trigger patterns

DATE-ISSUED: August 25, 1992

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Brockton

De Angelis; Douglas J. Woburn MA
Maddox; Henry W. J. Franklin MA
Peters; Arthur Sudbury MA
Rathbun; Donald J. Methuen MA

Saltmarsh; William L.

ASSIGNEE-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY TYPE CODE

Bull HN Information Systems Inc. Billerica MA 02

APPL-NO: 07/ 455664 [PALM]
DATE FILED: December 22, 1989

INT-CL: [05] G06F 11/34

US-CL-ISSUED: 395/575; 364/267, 364/267.2

US-CL-CURRENT: 714/39

FIELD-OF-SEARCH: 371/19, 371/15.1, 371/16.1, 364/2MSFile, 364/9MSFile

PRIOR-ART-DISCLOSED:

U.S. PATENT DOCUMENTS

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PAT-NO	ISSUE-DATE	PATENTEE-NAME	US-CL
3707725	December 1972	Dellheim	371/19
4100532	July 1978	Farnback	340/146.3MA
4445192	April 1984	Haag et al.	364/900
4651298	March 1987	Currier, Jr.	364/900
4845615	July 1989	Blasciak	364/200

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 4937740
 July 1990
 Agawal et al.
 371/19

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 March 1991
 Stark et al.
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ART-UNIT: 236

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ABSTRACT:

A monitor for selectively detecting and recording conditions at selected points within a system includes a trigger memory for storing patterns of trigger signals, wherein each pattern of trigger signals corresponds to a selected condition to be detected on first points of the system. The trigger memory includes a first port having a read address input connected from the first points and a data output connected to trigger output logic for providing patterns of trigger signals corresponding to the conditions to be detected. Each pattern of trigger signals is stored in the trigger memory location whose address corresponds to a pattern of signals from the first points representing the corresponding condition to be detected. The trigger memory is a dual port memory having a second port with a write address input and a data input for receiving trigger patterns to be stored therein. The method for generating the trigger patterns includes generating a first trigger pattern map and, from the first map, a second trigger pattern map to be written into a trigger memory which includes a plurality of submemories, wherein each submemory stores a portion of the trigger patterns.

6 Claims, 4 Drawing figures

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